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Product Manager
Engineering, IHS APAC

中国 Nov 2007






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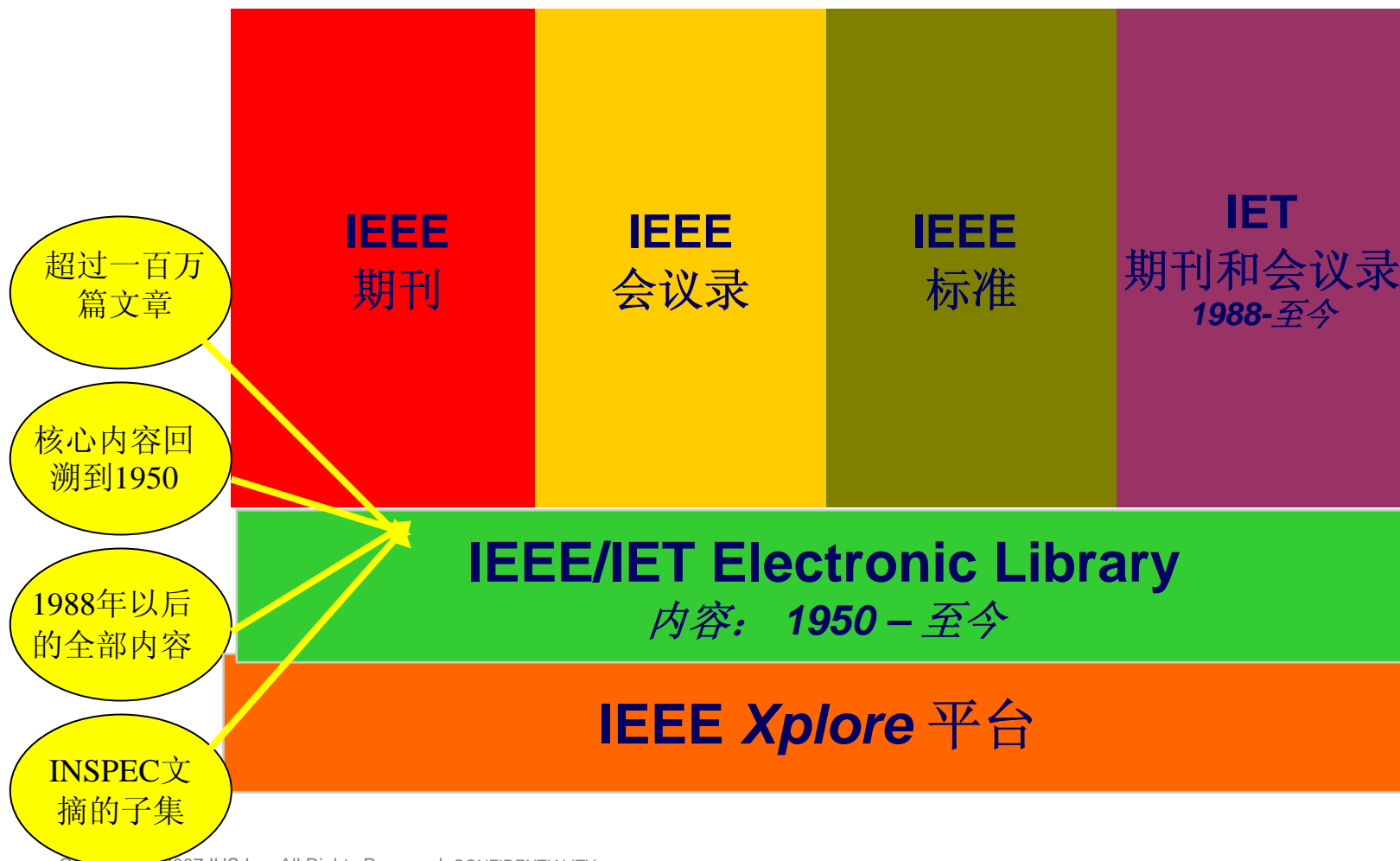
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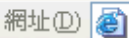
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95	95 Active	95-2002	Active - IEEE recommended practice for insulation testing of AC electric machinery (2300 V and above) with high direct voltage Revision of 95-1977
95	95 Archive	95-1977	Archived - IEEE Recommended Practice For Insulation Testing Of Large AC Rotating Machinery With High Direct Voltage
96	96 Archive	96-1969	Withdrawn - IEEE general principles for rating electric apparatus for short-time, intermittent, or varying duty Withdrawn 19 March 1998

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802.11b-1999/Cor 1-2001	IEEE standard for information technology - telecommunications and information exchange between systems - local and metropolitan area networks - specific requirement. Part 11: wireless LAN medium access control (MAC) and Physical layer (PHY) specifications. Amendment 2: higher-speed physical layer (PHY) extension in the 2.4 GHz band - corrigendum 1
802.15.4-2006	IEEE Standard for Information technology- Telecommunications and information exchange between systems- Local and metropolitan area networks- Specific requirements Part 15.4: Wireless Medium Access Control (MAC) and Physical Layer (PHY) Specifications for Low-Rate Wireless Personal Area Networks (WPANs) <u>Revision of 802.15.4-2003</u>
802.16/Conformance01-2003	IEEE standard for conformance to IEEE 802.16 part 1: protocol implementation conformance statement (PICS) proforma for 10-66 GHz wireless MAN-SC air interface
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Designation: 802.11-1999

Sponsor: IEEE Computer Society/Local and Metropolitan Area Networks

Reaffirmation status and year: 2003

Title: Standard for Information Technology - Telecommunications and information exchange between systems - Local and Metropolitan Area networks - Specific requirements - Part 11: Wireless LAN Medium Access Control (MAC) and Physical Layer (PHY) specifications

Status: Approved Publication of IEEE **802.11, 2003 Edition

Publication type: Special Publication

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History: PAR APP: Dec 09, 1997, BD APP: Mar 18, 1999, ANSI APP: Jul 15, 1999

Project scope: To rectify a number of errors in the current standard and to accommodate input from the JTC1 review to result in a single JTC1/IEEE standard.

Project purpose: To correct errors found in reviewing interpretation requests to the current standard and from JTC1 review.

Abstract: "802-11-1999.pdf, Part 11: Wireless LAN Medium Access Control (MAC) and Physical Layer (PHY) Specifications"

Keywords: "The scope of this standard is to develop a medium access control (MAC) and physical layer (PHY) specification for wireless connectivity for fixed, portable, and moving stations within a local area."

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INSPEC Accession Number: 8029642
Year: 2002
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Status: [Revision of 802-1990](#)

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 - [802b-2004](#) **Active** - IEEE Std 802b - 2004 IEEE Standard for Local and Metropolitan Area Networks: Overview and Architecture
 - 802 Archives
 - [802-1955](#) **Withdrawn** - Proposed test code for direct-current carbon-pile voltage regulators for aircraft
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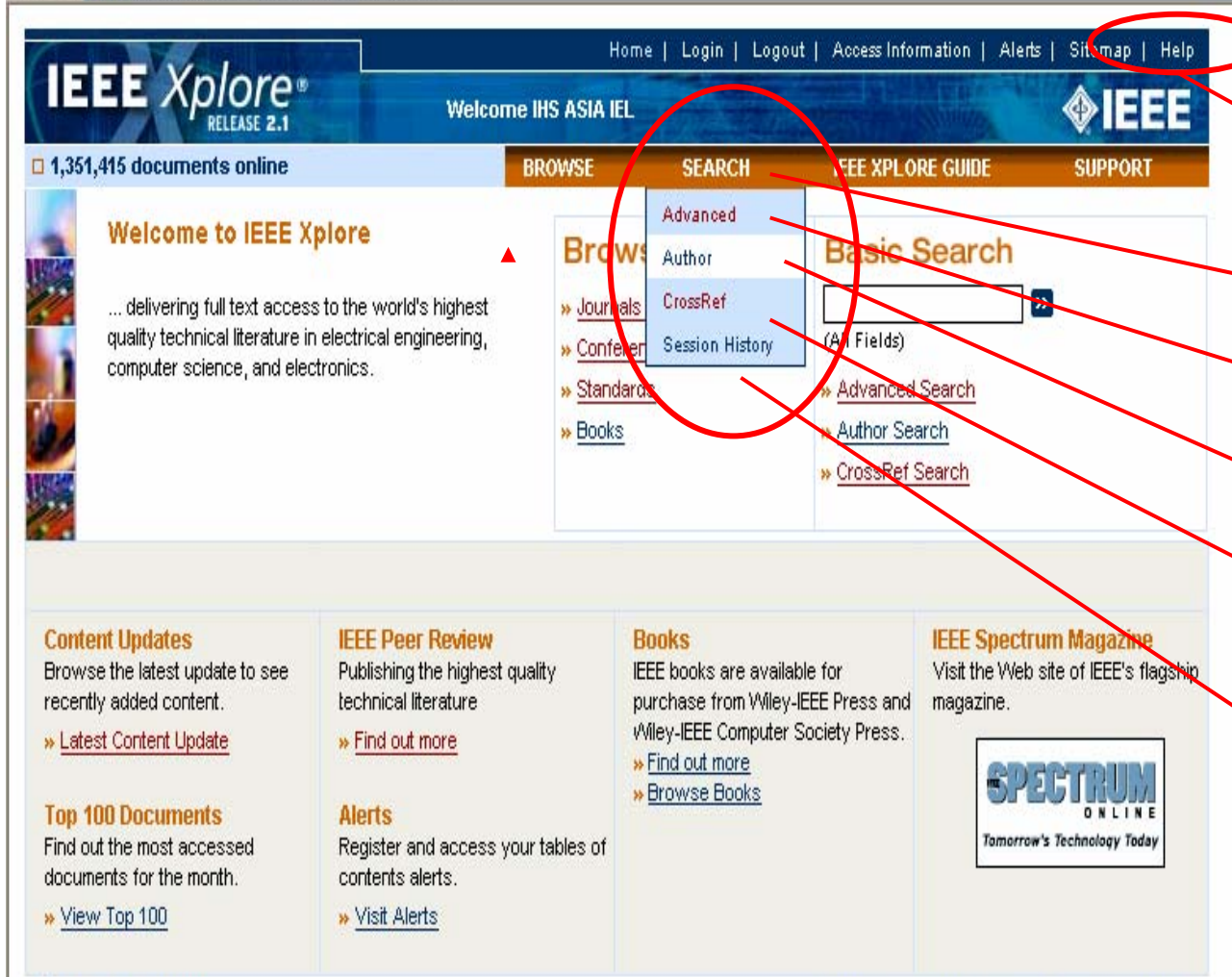
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Author Search BROWSE SEARCH IEEE XPLORE GUIDE SUPPORT

OPTION 1
Quick Find an Author:
Enter a name to locate articles written by that author.
 >>
Example: Enter Lockett S to obtain a list of authors with the last name Lockett and the first initial S.

OPTION 2
Browse alphabetically
Select a letter from the list.
[A](#) [B](#) [C](#) [D](#) [E](#) [F](#) [G](#) [H](#) [I](#) [J](#) [K](#) [L](#) [M](#) [N](#) [O](#) [P](#) [Q](#) [R](#) [S](#) [T](#) [U](#) [V](#) [W](#) [X](#) [Y](#) [Z](#)

Select a name to view articles written by that author

Lange A.	Lange A. A.	Lange A. C.
Lange A. E.	Lange B.	Lange B. M.
Lange C.	Lange C. -F.	Lange C. F.
Lange C. H.	Lange Chr.	Lange D.
Lange D. B.	Lange D. H.	Lange D. J.
Lange D. N.	Lange D. S.	Lange E.
Lange F.	Lange F. F.	Lange F. J. K.
Lange G.	Lange G. -M.	Lange G. A.
Lange G. W.	Lange H.	Lange H. -J.
Lange H. R.	Lange J.	Lange J. F.
Lange J. H. Jr.	Lange J. M.	Lange J. R.
Lange J. S.	Lange K.	Lange K. -J.
Lange K. L.	Lange K. P.	Lange L.
Lange L. K.	Lange M.	Lange M. D.
Lange M. J.	Lange M. L.	Lange M. M.
Lange M. R.	Lange N.	Lange N. Y.
Lange O.	Lange P.	

Next 14

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•输入作者的姓

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•作者Lange A.
从1950至今总
共在IEEE发
表153篇文章

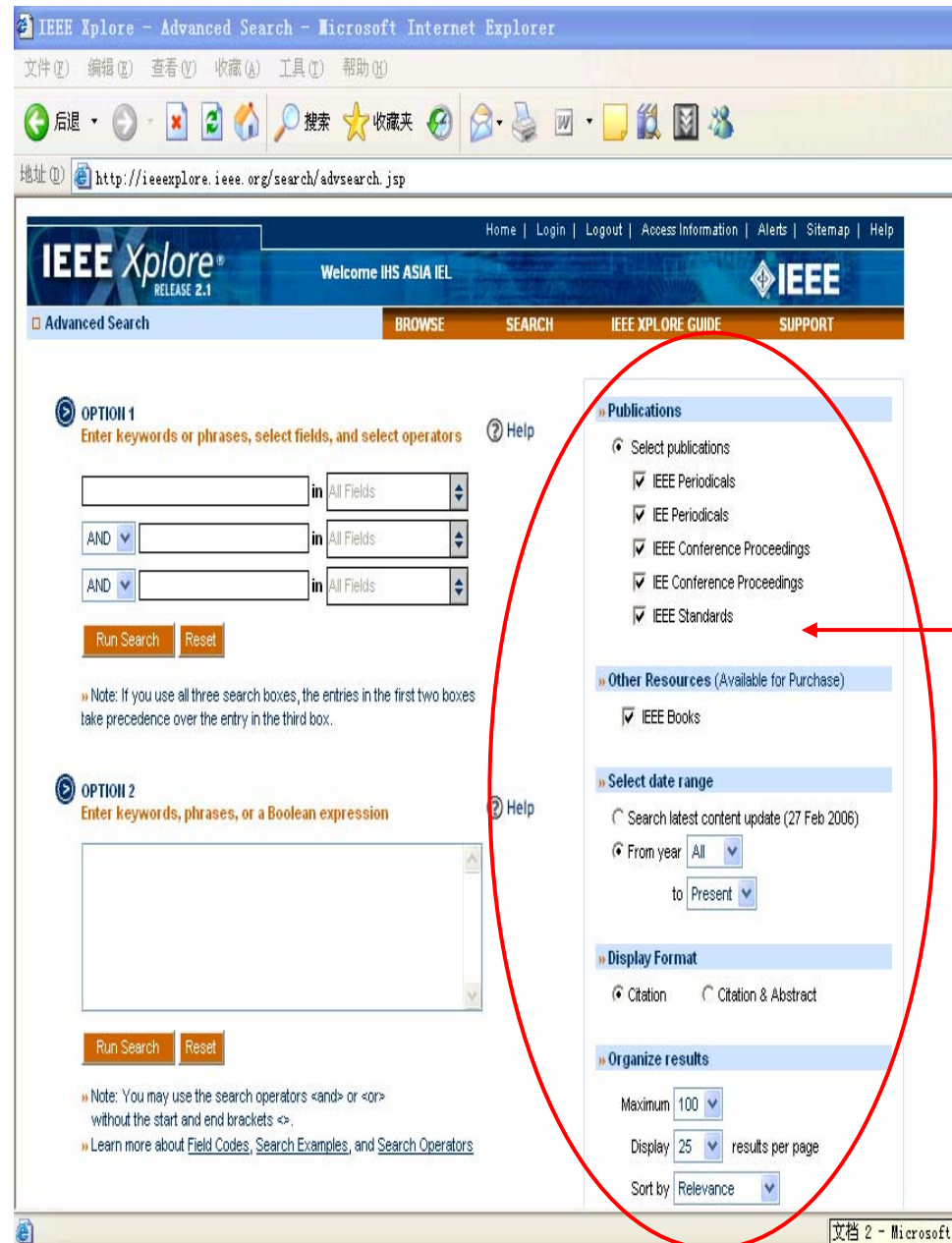
•选择检索结
果清单每篇文
章简易资讯或
详细资讯

The screenshot shows the IEEE Xplore search results page for the author 'Lange A.'. The browser window title is 'IEEE Xplore Search Result - Microsoft Internet Explorer'. The address bar shows the URL: [http://ieeexplore.ieee.org/search/searchresult.jsp?disp=cit@queryText=\(lange%20a.<in>au\)&valnm=Lange+A.&history=yes](http://ieeexplore.ieee.org/search/searchresult.jsp?disp=cit@queryText=(lange%20a.<in>au)&valnm=Lange+A.&history=yes). The page content includes:

- Navigation links: Home | Login | Logout | Access Information | Alerts | Sitemap | Help
- Search Results summary: Results for "(lange a.<in>au)". Your search matched 153 of 1322957 documents. A maximum of 100 results are displayed, 25 to a page, sorted by Relevance in Descending order.
- Search Options: View Session History, New Search
- Key: IEEE JMI (IEEE Journal or Magazine), IEEE JNL (IEE Journal or Magazine), IEEE CNF (IEEE Conference Proceeding), IEE CNF (IEE Conference Proceeding), IEEE STD (IEEE Standard)
- Modify Search: (lange a.<in>au) Search
- Display Format: Citation Citation & Abstract
- view selected items Select All Deselect All View: 1-25 | 26-50 | 51-75 | 76-100
- Search Results List:
 1. Deterministic cavity-QED with single ions
Keller, M.; Lange, B.; Lange, W.; Walther, H.; Hayasaka, K.;
[Quantum Electronics Conference, 2003. EQEC '03. European](#)
22-27 June 2003 Page(s):390
[AbstractPlus](#) | Full Text: PDF(238 KB) IEEE CNF
[Rights and Permissions](#)
 2. Cluster analysis of dynamic cerebral contrast-enhanced perfusion MRI time-series
Wismuller, A.; Meyer-Baese, A.; Lange, O.; Reiser, M.F.; Leinsinger, G.;
[Medical Imaging, IEEE Transactions on](#)
Volume 25, Issue 1, Jan. 2006 Page(s):62 - 73
Digital Object Identifier 10.1109/TMI.2005.861002
[AbstractPlus](#) | Full Text: PDF(2096 KB) IEEE JNL
[Rights and Permissions](#)
 3. Strategies for environmentally sound economic development an
Duchin, F.; Lange, G.-M.;
Power Engineering Review. IEEE



进阶检索页面



两种 Search
查询功能

检索结果
范围排
序设定



使用进阶检索 Advance Search 寻找期刊举例 Journal Search Example



- 条件:

文章名称: *Sample Data Holds*

期刊名: *Automatic Control*

作者: *Leonard*

IEEE Xplore - Advanced Search - Microsoft Internet Explorer

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Advanced Search BROWSE SEARCH IEEE XPLORE GUIDE SUPPORT

OPTION 1
Enter keywords or phrases, select fields, and select operators

sample data holds in Document Title

AND automatic control in Publication Title

AND leonard in Author

Run Search Reset

Note: If you use all three search boxes, the entries in the first two boxes take precedence over the entry in the third box.

OPTION 2
Enter keywords, phrases, or a Boolean expression

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Note: You may use the search operators <and> or <or> without the start and end brackets <>.
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Publications

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 - IEEE Periodicals
 - IEE Periodicals
 - IEEE Conference Proceedings
 - IEE Conference Proceedings
 - IEEE Standards

Other Resources (Available for Purchase)

- IEEE Books

Select date range

- Search latest content update (27 Feb 2006)
- From year All to Present

Display Format

- Citation Citation & Abstract

Organize results

- Maximum 100
- Display 25 results per page
- Sort by Relevance

现成条件输入
栏并选择检索
字的栏位

辅助检索限制条件
检索结果排序选择框

检索结果

地址 http://ieeexplore.ieee.org/search/searchresult.jsp?query1=sample+data+holds@scope1=ti@op1=and&query2=automatic+contro

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Search Results BROWSE SEARCH IEEE XPLORE GUIDE SUPPORT

Results for "((sample data holds<in>ti) <and> (automatic control<in>jn))<and> (leo..."
Your search matched 1 of 1322957 documents.
A maximum of 100 results are displayed, 25 to a page, sorted by Relevance in Descending order.

View Session History
New Search

Modify Search
((sample data holds<in>ti) <and> (automatic control<in>jn))<and> (le Search
 Check to search only within this results set
Display Format: Citation Citation & Abstract

view selected items Select All Deselect All

1. First-order optimal reduced-delay sample-data holds
Leonard, F ;
[Automatic Control, IEEE Transactions on](#)
Volume 44, Issue 7, July 1999 Page(s):1446 - 1449
Digital Object Identifier 10.1109/9.774120
[AbstractPlus](#) | [References](#) | Full Text: [PDF\(128 KB\)](#) IEEE JNL
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可再输入条件缩小范围

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看到文件本文

按'Abstract'可看到
文件摘要部份

Abstract結果

文件摘要部份为
INSPEC .

- 文件 (ti)
- 作者名称 (au)
- 所属单位背景 (cs)
- 期刊名称 (jn)
- 发行年份 (py)
- 卷号 (vo)
- 国际书码 (is)
- 摘要 (ab)
- 文章专有名词 (de)

The screenshot shows a web browser window displaying search results from IEEE Explore. The address bar shows the URL: <http://ieeexplore.ieee.org/search/srchabstract.jsp?arnumber=774120&isnumber=16797&punumber=9&k2dockey=774120&ieejrns&query=X26+X26+sam>. The page title is "View Search Results".

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First-order optimal reduced-delay sample-data holds

Leonard F.
Process Dept., Ecole Nat. d'Ingenieurs de Metz, France,

This paper appears in: **Automatic Control, IEEE Transactions on**
Publication Date: July 1999
Volume: 44, Issue: 7
On page(s): 1446 - 1449
ISSN: 0018-9286
CODEN: IETAA9
INSPEC Accession Number: 6303121
Digital Object Identifier: 10.1109/9.774120
Posted online: 2002-08-06 22:32:25.0

Abstract
A data-holding scheme whose phase delay is significantly less than that of the usual zero-order hold (ZOH) is presented. The improvement is achieved by means of simple additional software, and a standard ZOH device is employed

Index Terms
Inspe
Controlled Indexing
[closed loop systems](#) [delay systems](#) [extrapolation](#) [filtering theory](#) [frequency response](#)
[optimal control](#) [sampled data systems](#)

Non-controlled Indexing
[closed loop systems](#) [extrapolation](#) [filtering](#) [frequency response](#) [phase delay](#) [sample-data holds](#) [sampled data systems](#) [zero-order hold device](#)

Author Keywords
Not Available

References
1 K. J. Astrom and B. Wittenmark, *Computer Controlled Systems* Englewood Cliffs, NJ: Prentice-Hall, 1990.
2 H. Hanselmann, "Implementation of digital controllers—A survey," *Automatica*, vol. 23, no. 1, pp. 7-32, 1987.



进阶检索 **Advanced Search Option 2** 的常用栏位简写 **(Field Codes)**



- **Abstract 摘要:** ab
- **Affiliation 所属单位:** cs
- **Article Title 文章名称:** ti
- **Author 作者:** au
- **Publication name 期刊名称:** jn
- **Subject term 专有名词:** de
- **Publication year 期刊标准发行年份:** py
- **Conference year 会议年份:** cy
- **Conference title 会议名称:** ct
- **ISSN, ISBN 国际书码:** is
- **Volume 卷号:** vo



进阶检索 Advanced Search Option 2 重要的运算元 (Operators)



X<in>Y: 关键字X属于栏位Y

X<and>Y: X与Y两条件一定要同时符合

X<or>Y: X与Y两条件任何一条件符合即可

<not>X: 排除X条件



IEEE Xplore - Advanced Search - Microsoft Internet Explorer

IEEE Xplore Help - Microsoft Internet Explorer

http://ieeexplore.ieee.org/search/advsearch.jsp

http://ieeexplore.ieee.org/xplshelp/Help_start.html#help_fieldcodes.html

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Advanced Search

OPTION 1
Enter keywords or phrases, select fields, and select

in All Fields

AND in All Fields

AND in All Fields

Run Search Reset

Note: If you use all three search boxes, the entries in the first two boxes take precedence over the entry in the third box.

OPTION 2
Enter keywords, phrases, or a Boolean expression

Run Search Reset

Note: You may use the search operators <and> or <or> without the start and end brackets <>.

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Summary of Field Codes

Field codes are elements that identify specific parts of an Abstract or a specific field, you can reduce the time it takes to process the search results. Here are the field codes you can use in search expressions.

Field Name	Field Code
Abstract	ab
Affiliation	cs
All fields	metadata
Author(s)	au
Catalog number	ca
CODEN	cn
Conference date	cy
Document title	ti
Editor(s)	au
Full text	pdfdata
Index term	de
ISBN	in
ISSN	in

Display 25 results per page

Sort by Relevance

Internet

进阶检索运算符简写提示



进阶检索 **Advanced Search**

Option 2 检索举例



- 条件:
 1. 文章名称有**Internet**与**Wireless**
 2. **1996**年至今，但不要**1999**年的资料
 3. 限定**IEEE**期刊杂志与会议记录



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OPTION 1
Enter keywords or phrases, select fields, and select operators

in All Fields

AND in All Fields

AND in All Fields

Run Search Reset

Note: If you use all three search boxes, the entries in the first two boxes take precedence over the entry in the third box.

OPTION 2
Enter keywords, phrases, or a Boolean expression

Run Search Reset

Note: You may use the search operators <and> or <or> without the start and end brackets <>.
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- Select publications
 - IEEE Periodicals
 - IEE Periodicals
 - IEEE Conference Proceedings
 - IEE Conference Proceedings
 - IEEE Standards

Other Resources (Available for Purchase)

- IEEE Books

Select date range

- Search latest content update (30 May 2006)
- From year to

Display Format

- Citation Citation & Abstract

Organize results

Maximum

Display results per page

Sort by

網際網路



进阶检索结果



IEEE Xplore# Search Result - Microsoft Internet Explorer

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地址 http://ieeexplore.ieee.org/search/searchresult.jsp?query1=@scope1=metadata@op1=and&query2=@scope2=metadata@op2=and&query3=@scope3=metada 转到 链接 >>

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Search Results **BROWSE** **SEARCH** **IEEE XPLORE GUIDE** **SUPPORT**

Results for "(internet<and>wireless<in>ti<not>(1999<in>py)) <and> (pyr >= 1996 &...)" e-mail printer friendly
 Your search matched **2953** of **1322957** documents.
 A maximum of **100** results are displayed, 25 to a page, sorted by **Relevance** in **Descending** order.

Search Options

[View Session History](#)

[New Search](#)

Key

- IEEE JIIL** IEEE Journal or Magazine
- IEE JIIL** IEE Journal or Magazine
- IEEE CNF** IEEE Conference Proceeding
- IEE CNF** IEE Conference Proceeding
- IEEE STD** IEEE Standard

Modify Search

(internet<and>wireless<in>ti<not>(1999<in>py)) <and> (pyr >= 1996 <and

Check to search only within this results set

Display Format: Citation Citation & Abstract

 [Select All](#) [Deselect All](#) **View:** [1-25](#) | [26-50](#) | [51-75](#) | [76-100](#)

- 1. Providing wireless Internet access in a TDMA/TDD wireless LAN through a new wireless packet fair queueing scheme**
 Xudong Wang;
[Vehicular Technology Conference, 2001. VTC 2001 Fall. IEEE VTS 54th](#)
 Volume 3, 7-11 Oct. 2001 Page(s):1319 - 1323 vol.3
 Digital Object Identifier 10.1109/VTC.2001.956410
[AbstractPlus](#) | Full Text: [PDF\(400 KB\)](#) **IEEE CNF**
[Rights and Permissions](#)

- 2. Truly seamless wireless and mobile host networking. Protocols for adaptive wireless and mobile networking**
 Johnson, D.B.; Maltz, D.A.;
[Personal Communications, IEEE \[see also IEEE Wireless Communications\]](#)
 Volume 3, Issue 1, Feb. 1996 Page(s):34 - 42
 Digital Object Identifier 10.1109/98.486974
[AbstractPlus](#) | Full Text: [PDF\(2400 KB\)](#) **IEEE JIIL**
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- ? 表示一个不明字母. eg. Ch?racter=Character
- * 代替一字符串. eg. Insti*=institute
- “searchtext” 搜寻结果不会为关键字做任何字形词性变化
- /sub x/ 下标符号 eg. h/sub 2/O = H₂O
- /sup x/ 上标符号 eg. r/sup 2/ = r²



进阶检索 **Advanced Search**

特殊符号与代用字符输入(**Special Character**)



/spl x/ 特殊符号输入.

Greek Letters

- 要使用希腊字母，请加/spl X/ X代表希腊字母

Name	Character	Code
• alpha	À	alpha
• beta	B	beta
• gamma	Γ	gamma
• delta	Δ	delta
• Infinity		infi



进阶检索 **Advanced Search** **Standard Search Example**



条件:

1. 文章名称含专有名词**H₂O**與**O₃**
2. 作者**Lahoz**



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Advanced Search | BROWSE | SEARCH | IEEE XPLORE GUIDE | SUPPORT

OPTION 1 Enter keywords or phrases, select fields, and select operators

in

AND in

AND in

Run Search Reset

Note: If you use all three search boxes, the entries in the first two boxes take precedence over the entry in the third box.

OPTION 2 Enter keywords, phrases, or a Boolean expression

LAHOZ<IN>AU<AND>H/SUB 2/O<IN>TI<AND>O/SUB 3/<IN>TI

Run Search Reset

Note: You may use the search operators <and> or <or> without the start and end brackets <>.

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Publications

- Select publications
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- IEEE Books

Select date range

- Search latest content update (27 Feb 2006)
- From year to

Display Format

- Citation Citation & Abstract

Organize results

- Maximum
- Display results per page
- Sort by



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文章摘要



IEEE Xplore® Search Result - Microsoft Internet Explorer

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地址(A) http://ieeexplore.ieee.org/search/searchresult.jsp?query1=@scope1=metadata&op1=and&query2=@scope2=metadata&op2=and&query3

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Search Results BROWSE SEARCH IEEE XPLORE GUIDE SUPPORT

Results for "**lahoz<in>au<and>h/sub 2/o<in>ti<and>o/sub 3/<in>ti**" e-mail printer friendly
 Your search matched **1** of **1322957** documents.
 A maximum of **100** results are displayed, **25** to a page, sorted by **Relevance** in **Descending** order.

» Search Options

[View Session History](#)

[New Search](#)

» Key

IEEE JIIL	IEEE Journal or Magazine
IEE JIIL	IEE Journal or Magazine
IEEE CNF	IEEE Conference Proceeding
IEE CNF	IEE Conference Proceeding
IEEE STD	IEEE Standard

Modify Search

Check to search only within this results set

Display Format: Citation Citation & Abstract

[Select All](#) [Deselect All](#)

- 1. The 183GHz H/sub 2/O 0/sub 3/ Channels On MLS**
 Lahoz, W.A.; [Geoscience and Remote Sensing Symposium, 1988. IGARSS '88. 'Remote Sensing: Moving Toward the 21st Century'. International Volume 2, 12-16 September 1988](#) Page(s):941 - 943
[AbstractPlus](#) | Full Text: [PDF\(236 KB\)](#) **IEEE CNF**
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http://ieeexplore.ieee.org/iel2/9/75/7617/00315852.pdf?isNumber=7617&number=315852 - Microsoft Internet Explorer provided by C

看PDF格式的文章



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The screenshot shows a Microsoft Internet Explorer browser window. The address bar contains the URL: `http://ieeexplore.ieee.org/iel5/6/28822/01296011.pdf?isNumber=28822&prod=JNL&number=28822146`. The browser's toolbar includes buttons for File, Edit, View, Favorites, Tools, and Help, along with navigation and zoom controls. The main content area displays a PDF document with text and a diagram of a lithography system. The diagram shows a wafer being processed by a mask illumination system and a projection lens. Red arrows point from the browser's toolbar to the PDF content, indicating actions like saving, zooming, and printing.

What a difference 10 years makes. Only 12 months ago the future of lithography—the core technology of the multi-billion-dollar microchip business of making chips, seemed straight forward. Optical lithography, the technique of using light to print onto a silicon wafer the wires, transistor parts, and everything else that make up an integrated circuit, was about to go the way of the Model T. Pressed to the very limits of its ability to print the vanishingly narrow arrays of lines, spaces, and contacts needed for upcoming generations of ICs, it would soon be replaced by extreme ultraviolet lithography, a sleek new technology propelled by the considerable commercial momentum of Intel Corp., Santa Clara, Calif.

But now, out of nowhere, a new technique has emerged that promises to breathe new life into optical lithography and put off until the next decade its replacement by extreme ultraviolet. And it seems to be just in time. In the semiconductor industry, where a good year's sales add up to a quarter-trillion dollars, a three-year revenue that late semiconductor work out the kinks in the still experimental technology of extreme ultraviolet lithography might just turn out to be the most timely and valuable pause in business history.

The upstart technology is known as immersion lithography. It accomplishes its life-extending wizardry by adding a tiny film of water between the wafer and the silicon wafer, allowing lithographic systems to print wires and spaces once thought impossibly narrow.

Even in an industry accustomed to accomplishing the seemingly impossible every 20 months or so, experts are nevertheless amazed by the speed with which the new optical technology has burst onto the scene. As a general rule, new lithographic systems take decades to develop. But in a space of less than two years, immersion has moved from an unknown to being the technology most likely to be used from 2007 through at least 2010.

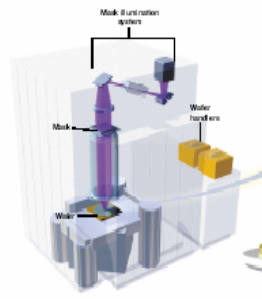
THE THREE MAJOR LITHOGRAPHY SYSTEM COMPANIES—ASML (the largest), in Veldhoven, the Netherlands, and Canon Inc. and Nikon Corp., both in Tokyo—consider its premise so great that they have started crash programs to develop the technology and now plan to deliver immersion systems to their chip-making customers within the next year or two. This is an incredible schedule, even in the fast-paced semiconductor industry, according to Wali Tiryakis, senior fellow, International Sematech, the Austin, Texas-based consortium of makers of semiconductor and of the tools used in their manufacture. “In a little more than a year, we’ve gone from a concept of plausibility to a schedule for delivery of tools. This has not happened before in the industry for a major technology revision,” says Tiryakis, who is also a fellow of the IEEE. By the end of last year, Nikon’s in-house development system had already printed components with dimensions smaller than 50 nanometers—a key requirement for the next generation of chips. Both ASML and Nikon have said that they will soon begin shipping systems to semiconductor development labs for further testing and evaluation in a setting more like that of a commercial plant. And Nikon has announced plans to start mass-producing them in 2005.

Yet another sign of the technology’s ascendance came at the recent Lithography Forum organized by Sematech. The purpose of the meeting, held this past January in Los Angeles, was simply to sort out the dazzling profusion of lithographic technologies developed to prepare for the anticipated crisis in optical

lithography. But the meeting came close to being a coronation for immersion lithography.

At the forum, developers of each technology, including the extreme ultraviolet approach heavily backed by Intel, gave a status report at the end of the conference, surveys polled the opinions of the attendees about the strengths and weaknesses of each approach. They were asked to rate the production readiness of each system and to predict the year that the technology would be ready for manufacturing. They were also asked detailed questions about each aspect of the technology that infrastructure, the ability to produce wafers at the required dimensions, and the cost. And they were asked which technology was most likely to be used to manufacture wafers in 2007, when the narrow lines on ICs are expected to be 66 nm, and in 2009, when they will dip down to a breathtaking 45 nm.

The overwhelming winner: immersion lithography. Attendees spurned extreme ultraviolet even though most of them thought



GETTING WATER WET Overall, 100 semiconductor wafer manufacturers litography systems looks just like the “dry” counterpart (above). But by adding a thin layer of water between the projection lens and the wafer, the wafer and system can create smaller features and do so at a lower cost. The technique involves coating the wafer and the lens with a thin layer of water, which then acts as a lens to reduce the wavelength of the light. The water is then removed and a fresh layer is applied before the wafer is put back in the lithography system for the next layer.

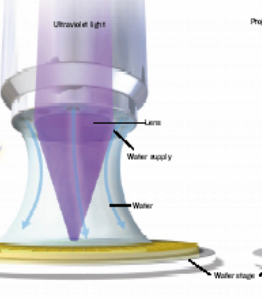
that it would be ready for manufacturing in just five years. (Details of some of the more detailed questions are posted on the Sematech Web site, <http://www.sematech.org/semtech/lib/01meeting/index.htm>.)

TO UNDERSTAND THE INGENUITY OF immersion lithography, start with its plain-old “dry” counterpart. On a wafer of prepared silicon, the current method produces hundreds of ICs, each consisting of perhaps hundreds of millions of transistors along with the interconnecting wires that make up a single IC.

On each wafer, the process of creation takes place IC by IC, layer by layer, starting with the transistor electrodes and ending with the contacts between different wire layers.

At the heart of this process, a beam of light passes through a stencil-like chrome-covered transparent plate called a mask. The chrome has been patterned with a magnified image of the particular layer of the IC being created in that step—for example, the transistor contacts. Where the chrome has been removed, the light passes through the mask and is focused by the projection lens onto the wafer, which has been coated with a photosensitive material. After an IC site has been exposed to the external light, the movable stage that supports the wafer repositions itself under the projection lens so that a different IC site can be exposed. The chrome-covered wafer is exposed to the light, the wafer is taken from the lithography system, and the now-soluble resist is rinsed away, leaving the desired image

of the mask on the wafer.



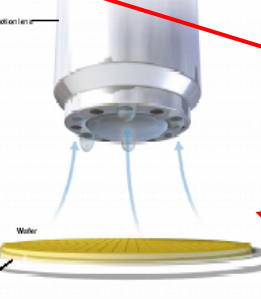
IN PLAINVIEW of the IC layer that is to be created. After the rinsing step, the wafer undergoes various other processes, such as ion implantation or deposition, which depend on the particular layer being formed. The remaining resist is then removed, and a fresh layer is applied before the wafer is put back in the lithography system for the next layer.

This process has worked amazingly well for about four decades, but it is now entering a twilight phase. The root cause of its anticipated demise is the wavelength of the light that the system uses to print all those layers of patterns. The resolution of the system—the narrowness of the wires and the spaces between them that the system is capable of printing—depends directly on the wavelength and inversely on a property of the optical system called the numerical aperture. So, to print really small details, you want either a small wavelength, or a large aperture, or, ideally, both.

The numerical aperture, roughly analogous to the f-stop in photography, is related to the product of two key characteristics of the lithography system: one is the widest angle through which light passing through the lens can be focused on the wafer, the other is the refractive index of the medium through which the light passes on its way to the wafer. The refractive index, in turn, is the ratio of the speed of light in a vacuum over its speed in the medium.

Air has a refractive index of 1, and a lithographic system operating in air has a numerical aperture between 0 and 1. Recall that what you want is the largest possible numerical aperture. One way of getting it, clearly, is by operating your lithographic system in a medium with a refractive index greater than that of air—in other words, greater than 1. But more on that later. Wouldn't it just be simpler to reduce the wavelength of the light? Yes, up to a point. And we're getting very close to that point.

To resolve the ever-shrinking wire widths demanded by an



INDUSTRY INTENT on shrinking them by 50 percent every two years or so, engineers and researchers have been pursuing the twin strategies of reducing wavelengths while also making lenses bigger to increase the numerical aperture. Almost all the while, they've been fretting that they are getting to the end of the line as far as optical wavelengths are concerned.

But each time the resolution of optical lithography seemed about to reach its limit, Heretofore technical advances kept the cycles going. From wavelengths of 426 nm and numerical apertures of 0.2 in early lithography systems, the wavelength now stands at 193 nm with numerical apertures of 0.86 in today's state-of-the-art commercial lithography systems. These will produce ICs with more than half a billion transistors and wires and spaces less than 100 nm wide.

Now, however, the approach of reducing wavelengths has come up against a brick wall. The reason is simple: light with a wave-

THE THREE LITHOGRAPHY CONTENDERS

193-NANOMETER IMMERSION 65-NM “DRY” LITHOGRAPHY EXTREME ULTRAVIOLET LITHOGRAPHY

Although system developers are confident they will find clear paths to the next generation of lithography, the road is not so sure. These with reservations include Karl Eason, lithography department director of the International Micro Electronics

US 450 million in funding over three years from Intel, to develop a production-worthy light source for extreme ultraviolet lithography, but there is no guarantee that it will be ready at the end of the three years—or even for the hoped-for 2009 commercial

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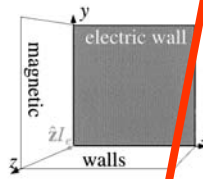


Fig. 1. Computational volume of the dipole radiating.

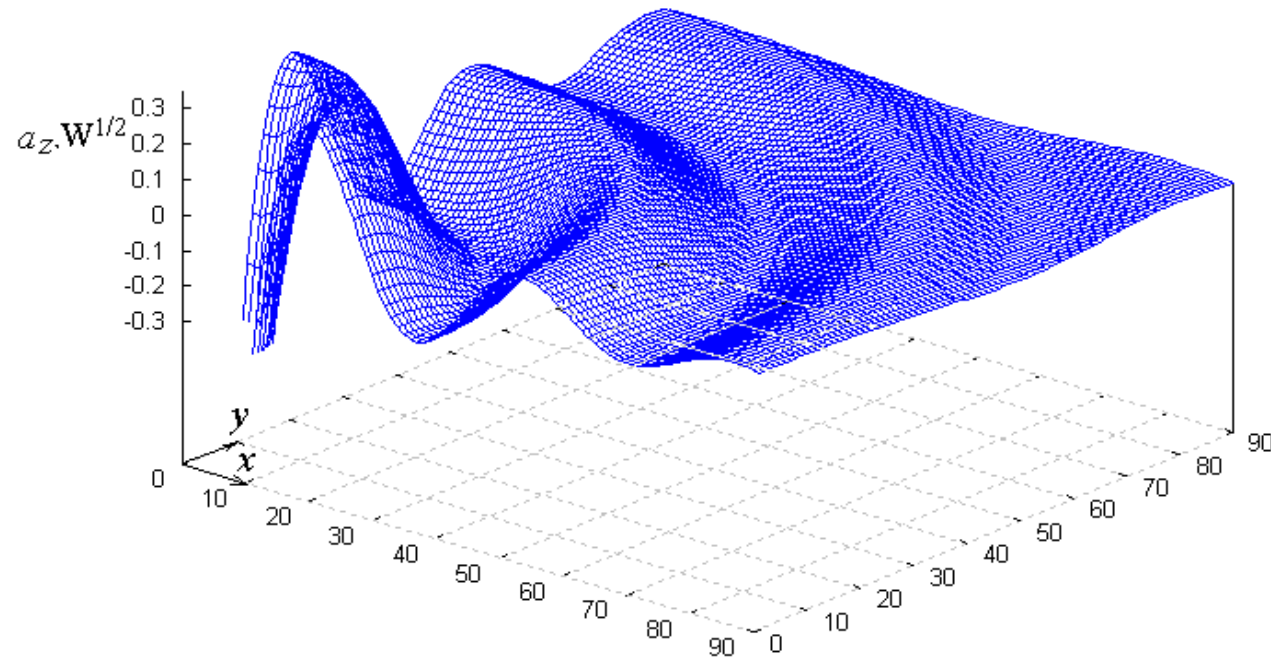
The operator $\nabla^2 - \mathcal{T}_{\mu\epsilon}$ defaults to the well-known $\nabla^2 - \mu\epsilon\partial_t^2$ in a loss-free medium. Notice that the “ordinary” vector potentials are

$$\begin{aligned} \mathbf{A}_\mu &= \mu^{-1} \mathbf{A} \\ \mathbf{F}_\epsilon &= \epsilon^{-1} \mathbf{F}. \end{aligned}$$

As a first example, let us consider the field of a very small dipole (electric current element) we set as $\mathbf{J}_e = \hat{z}J_{ez}$ in the x - 0 - y -plane. According to (13), a spherical $\mathbf{A}_\mu = \hat{z}A_{\mu z}$ wave propagates in open space. We examine this wave when the sinusoidal function of time.

We simulate numerically this problem using a reference algorithm based on the time-domain (TDWP) approach [28], which solves the specified boundary conditions and medium. The volume (see Fig. 1) includes only one octant of the symmetry of the problem. There is an electric wall at $x = 0$ and $y = 0$, and magnetic walls at $x = L$ and $y = L$. The three boundaries employ absorbing boundaries to simulate reflection-free propagation. The normalized potentials $a = \sqrt{Z_0} A_\mu$ and f measured in $W^{1/2}$. Here, $Z_0 = \sqrt{\mu_0/\epsilon_0}$ is the impedance of vacuum.

In the z -oriented dipole example, a single normalized potential $a = \hat{z}a_z$ is computed and the wave in the x - 0 - y -plane is animated in 3D. In all examples considered in this paper, the computational volume is discretized into a uniform mesh. For the example at hand, we choose a spatial step size $\Delta h = \lambda/30$, where λ is the wavelength in free space corresponding to the frequency of the excitation current ($\lambda = 1$ m). The x - and y -axes in the animation are scaled in terms of the spatial step Δh . For example, the point (30, 45) has actual coordinates $x = 30\Delta h$, $y = 45\Delta h$ with respect to the



$$-\mathcal{T}_\mu \Psi = \nabla \cdot \mathbf{F}_\epsilon. \quad (20)$$

The vector operators $(\nabla \mathcal{T}_\epsilon)$ and $(\nabla \mathcal{T}_\mu)$ are the gradients of the operators defined in (14) as follows:



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Nara Inst. of Sci. & Technol., Japan

This paper appears in: **Electronics Letters**
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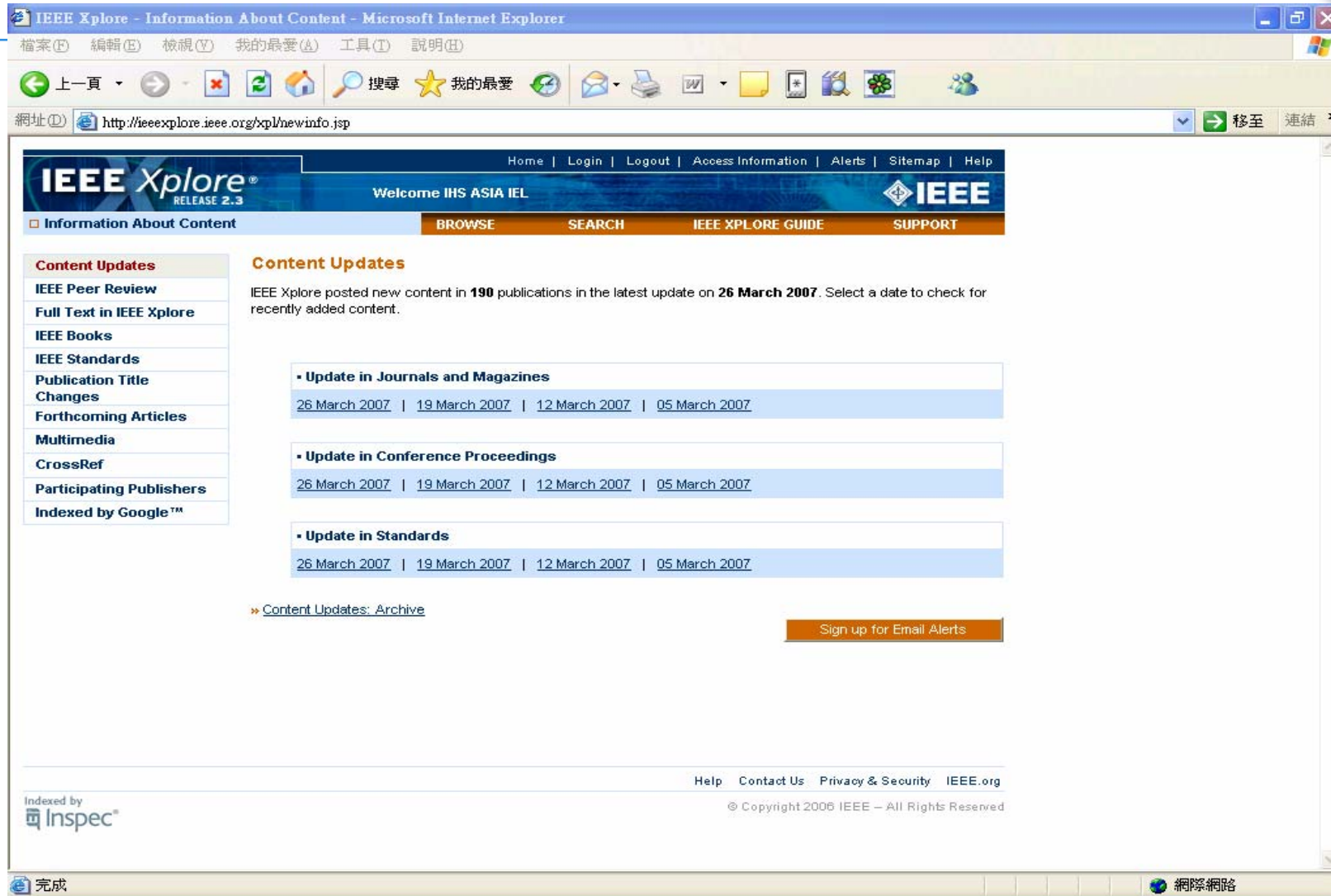
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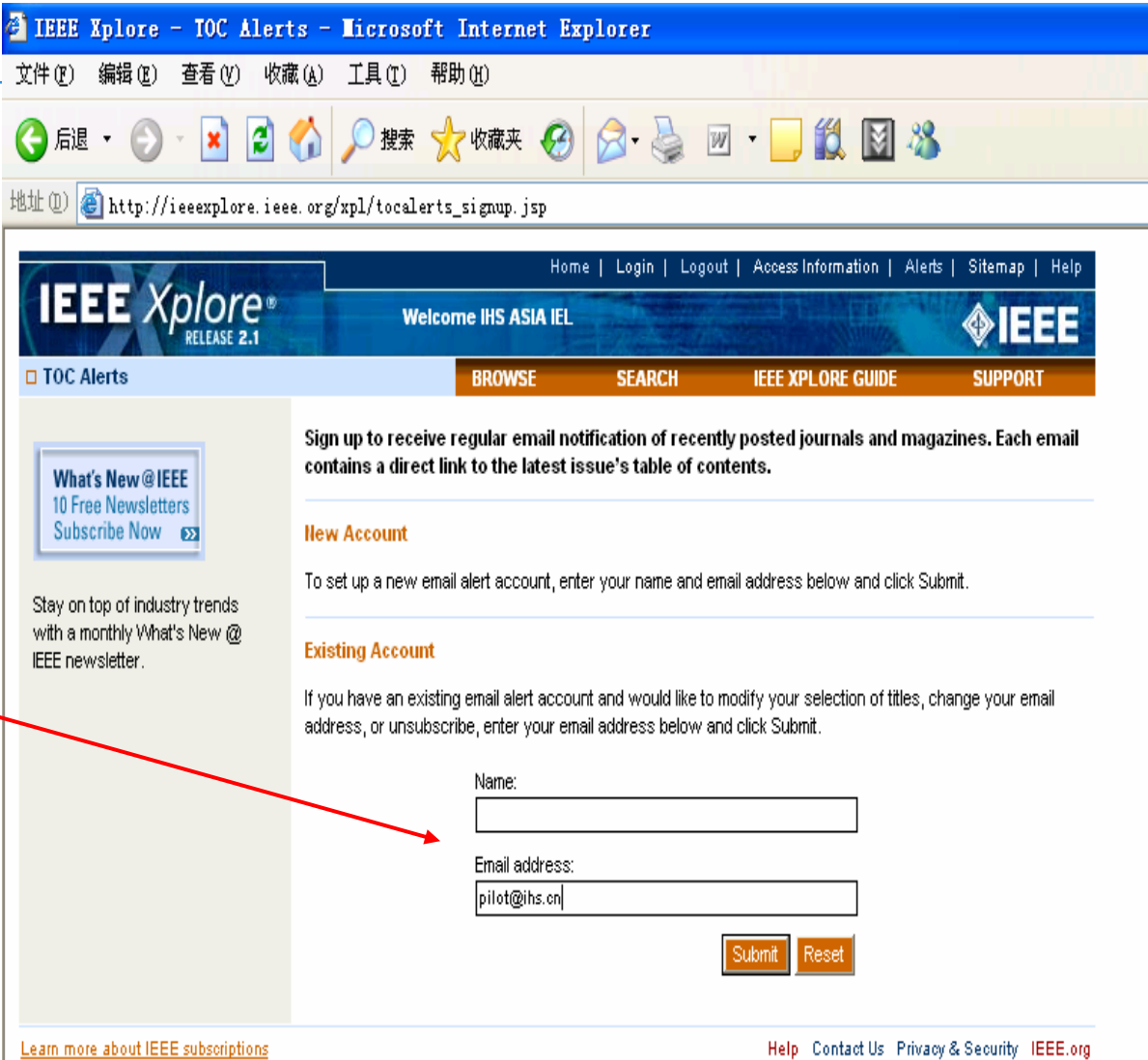
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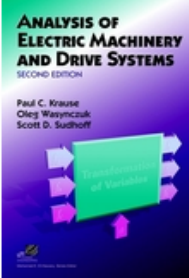
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- IEEE Xplore 工具栏
- 检索功能的增加
 - 检索结果按钮，著名条目的检索
 - 检索的操作说明指南
- **SSL**（安全锁）
- 技术调研资料
- 引用下载– 多了**Refworks** 和 **Bibtex** 格式可以选择
- 检索结果的改进



2007年第三季IEEE Xplore 2.3.1发布

- IEEE Xplore 工具栏
 - 检索功能的增加
 - 检索结果按钮，著名条目的检索
 - 检索的操作说明指南
 - SSL（安全锁）
 - 技术资料调研
 - 引用下载—多了Refworks 和 Bibtex 格式可以选择
 - 检索结果的改进



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Top Documents Accessed: Feb 2006

Display Format: Citation Citation & Abstract

Article Information

- Antenna design for UHF RFID tags: a review and a practical application**
Rao, K.V.S.; Nikitin, P.V.; Lam, S.F.
Antennas and Propagation, IEEE Transactions on
Volume 53, Issue 12, Date: Dec. 2005, Pages: 3870- 3876
Digital Object Identifier 10.1109/TAP.2005.859919
[Abstract](#) | Full Text: [PDF](#) (808 KB)
- Novel small-size directional antenna for UWB WBAH/WPAH applications**
Klemm, M.; Kovacs, I.Z.; Pedersen, G.F.; Troster, G.
Antennas and Propagation, IEEE Transactions on
Volume 53, Issue 12, Date: Dec. 2005, Pages: 3884- 3896
Digital Object Identifier 10.1109/TAP.2005.859906
[Abstract](#) | Full Text: [PDF](#) (2064 KB)
- List of Reviewers for 2005**
Antennas and Propagation, IEEE Transactions on
Volume 54, Issue 1, Date: Jan. 2006, Pages: 302- 306



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Frequency: 6

ISSN: 1063-6692

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Published by: [IEEE Communications Society](#)
[IEEE Computer Society](#)
[Association for Computing Machinery](#)

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Announcements

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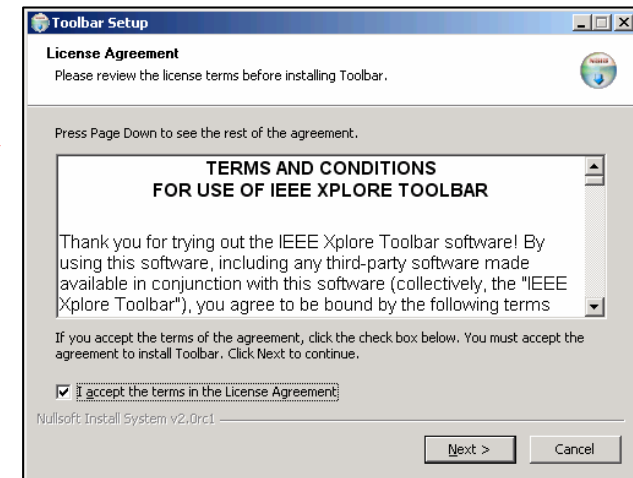
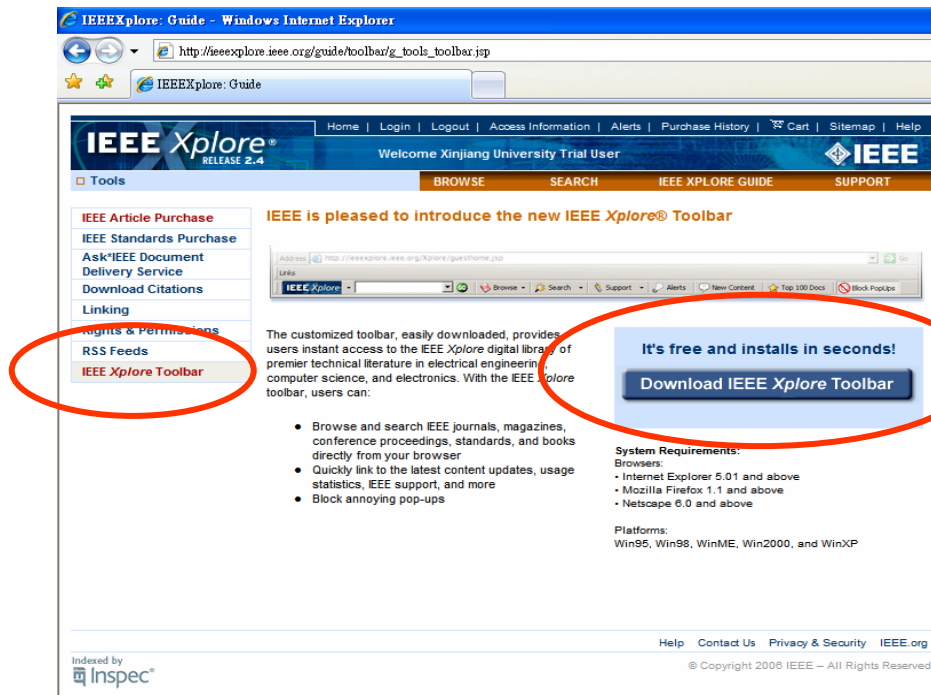
The screenshot shows the IEEE Xplore website interface. At the top, there is a navigation bar with links for Home, Login, Logout, Access Information, Alerts, Sitemap, and Help. Below this is the IEEE Xplore logo and the text 'RELEASE 2.0'. A secondary navigation bar contains 'IEEE Conference Proceedings', 'BROWSE', 'SEARCH', 'IEEE XPLORE GUIDE', and 'SUPPORT'. The main content area displays the title 'Information Visualization, 2006. INFOVIS 2006. IEEE Symposium on' and an 'OPAC Link' with the URL 'http://xplqa.ieee.org/servlet/opac?punumber=2945' and a 'Learn more' link. A text box highlights the sentence: 'This conference has been published in [Visualization and Computer Graphics, IEEE Transactions on, Volume 12 Issue 5.](#)' A red arrow points from this text box to a callout box on the right.

快捷链接查看 期刊包含的
会议录内容



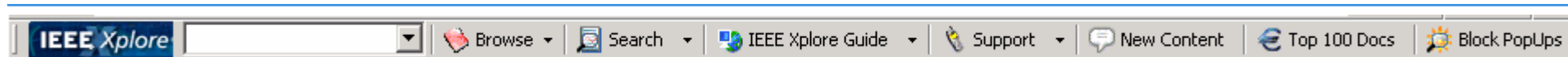
客户可以把IEEE Xplore 加到他们自己的浏览器中

- 这项功能在IEEE Xplore Guide的工具栏(Tools)中可以找到
- 允许 远程访问IEEE Xplore
- 需要安装插件程序





IEEE Xplore 工具栏提供快速访问



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检索功能的增加使得用户能快速找到检索结果

- 检索结果按钮的增加使得检索更加便利
- 著名出版物检索

知名刊物的检索极大的节约了用户的时间

Coming Soon!



- 可已使用 DOI, INSPEC Accession # or specific fields
- 多输入几个检索的领域帮助找到检索结果

The screenshot shows the IEEE Xplore website's citation search page. At the top, there is a navigation bar with links for Home, Login, Logout, Access Information, Alerts, Sitemap, and Help. Below this is a header with the IEEE Xplore logo (RELEASE 2.1) and a 'Welcome IEL Customer' message. A secondary navigation bar contains 'Citation Search', 'BROWSE', 'SEARCH', 'IEEE XPLORE GUIDE', and 'SUPPORT'. The main content area features a heading: 'Use this search if you know the citation for a specific document in IEEE Xplore.' followed by a sub-heading: 'If an exact match is not found, up to 5 results will be displayed. Results are sorted by Relevance.' Below this, there are three radio button options for document search: 'DOI (Digital Object Identifier) - Example: 10.1109/TADVP.2004.841649', 'INSPEC Accession Number - Example: 8298046', and 'Word(s) in document title - Example: Model Quality in Identification of Nonlinear Systems'. The third option is selected. A text input field is provided for the selected option. Below this, a section titled 'The following fields are only enabled when "Word(s) in document title" is selected:' contains several input fields: Author, Year, Volume, Issue, Start Page, and End Page. A 'Publication:' label is followed by a text input field and two radio button options: 'Word(s) in publication title' and 'ISSN or ISBN'. At the bottom of the form are two buttons: 'Run Search' and 'Clear Search'.

Coming Soon!



知名项目的检索

- 可以直接进行 targeted search
- 举例 :把检索结果限定到 “Trivedi” 和 “170 – 200 页”

The screenshot shows the IEEE Xplore search interface. At the top, there is a navigation bar with links for Home, Login, Logout, Access Information, Alerts, Sitemap, and Help. Below this is a banner for IEEE Xplore Release 2.1, welcoming IEL customers, and a navigation menu with BROWSE, SEARCH, IEEE XPLORE GUIDE, and SUPPORT. The main content area is titled "Citation Search" and includes instructions: "Use this search if you know the citation for a specific document in IEEE Xplore. If an exact match is not found, up to 5 results will be displayed. Results are sorted by Relevance." There are three radio button options for document search: "DOI (Digital Object Identifier) - Example: 10.1109/TADVP.2004.841649", "INSPEC Accession Number - Example: 8298046", and "Word(s) in document title - Example: Model Quality in Identification of Nonlinear Systems". The third option is selected. Below this is a text input field. A section titled "The following fields are only enabled when 'Word(s) in document title' is selected:" contains several input fields: Author (trivedi), Year, Volume, Issue, Start Page (170), and End Page (200). There is also a "Publication:" field with two radio button options: "Word(s) in publication title" and "ISSN or ISBN". At the bottom, there are "Run Search" and "Clear Search" buttons.

- DOI
- Inspec #
- Word (s) in Title
- Multiple Fields

检索结果按钮改进了用户访问内容的途径

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Home | Login | Logout | Access Information | Alerts | Sitemap | Help

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Welcome Research Account

Search Results BROWSE SEARCH IEEE XPLORE GUIDE SUPPORT

Results for "(java)<in>metadata"
Your search matched 5086 of 1461305 documents.
A maximum of 100 results are displayed, 25 to a page, sorted by Relevance in Descending order.

Search Options
View Session History
New Search

Key

- IEEE JIIL IEEE Journal or Magazine
- IEE JIIL IEE Journal or Magazine
- IEEE CHF IEEE Conference Proceeding
- IEE CHF IEE Conference Proceeding
- IEEE STD IEEE Standard

Modify Search
((java)<in>metadata) Search

Check to search only within this results set

Display Format: Citation Citation & Abstract

IEEE IET BOOKS Expert How Application Notes Scho

view selected items Select All Deselect All View: 1-25 | 26-50 |

1. Java, Java, Java
Sabharwal, C.L.;
[Potentials, IEEE](#)
Volume 17, Issue 3, Aug-Sep 1998 Page(s):33 - 37
Digital Object Identifier 10.1109/45.714612
[AbstractPlus](#) | Full Text: [PDF\(1896 KB\)](#) IEEE JIIL
[Rights and Permissions](#)

2. Java Business Integration
Vinoski, S.;

检索结果依据内容的类型进行分类

- IEEE/IET 默认内容浏览
- 其他内容比如 从以前的左手边换到了现在的位置
- 额外的一些内容比如 操作说明书与IEEE/IET 分开了
- 动态标签页 – 基于访问和查找的标准可以正常显示

检索结果的排列是从最靠近的开始

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IEEE Xplore[®] RELEASE 2.1

Home | Login | Logout | Access Information | Alerts | Sitemap | Help

Welcome IEL Customer

IEEE

Search Results BROWSE SEARCH IEEE XPLORE GUIDE SUPPORT

Xplore found no Results for "(trivedi<in> au) <and>(sp<contains>170) <and>(ep<contains>200)".
This is the closest match for your query.

View Session History
New Search

Key

IEEE JIIL	IEEE Journal or Magazine
IET JIIL	IET Journal or Magazine
IEEE CHF	IEEE Conference Proceeding
IET CHF	IET Conference Proceeding
IEEE STD	IEEE Standard

- 1. A Binary Tree for Probability Learning in Eye Detection**
Junwen Wu; Trivedi, M.M.;
[Computer Vision and Pattern Recognition, 2005 IEEE Computer Society Conference on](#)
Volume 3, 20-26 June 2005 Page(s):170 - 170
Digital Object Identifier 10.1109/CVPR.2005.562
[AbstractPlus](#) | Full Text: [PDF\(520 KB\)](#) **IEEE CHF**
[Rights and Permissions](#)
- 2. Book Reviews**
[Systems Science and Cybernetics, IEEE Transactions on](#)
Volume 5, [Issue: 2](#) April 1969 Page(s):170 - 171
Digital Object Identifier 10.1109/TSSC.1969.300212
[AbstractPlus](#) | Full Text: [PDF\(1131 KB\)](#) **IEEE JIIL**
[Rights and Permissions](#)
- 3. New Color Picture Tube System for Portable TV Receivers**
Barbin, R.L.; Hughes, R.H.;
[Broadcast and Television Receivers, IEEE Transactions on](#)
Volume BTR-18, [Issue: 3](#) Aug. 1972 Page(s):193 - 200
Digital Object Identifier 10.1109/TBTR1.1972.299669
[AbstractPlus](#) | Full Text: [PDF\(4906 KB\)](#) **IEEE JIIL**
[Rights and Permissions](#)
- 4. 25-V Inch 114-Degree Trinitron Color Picture Tube and Associated New Developments**
Yoshida, S.; Ohkoshi, A.; Miyaoka, S.;
[Broadcast and Television Receivers, IEEE Transactions on](#)
Volume BTR-20, [Issue: 3](#) Aug. 1974 Page(s):193 - 200
Digital Object Identifier 10.1109/TBTR1.1974.299845
[AbstractPlus](#) | Full Text: [PDF\(4050 KB\)](#) **IEEE JIIL**
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如果没有最确切的检索结果, 最接近的5个结果将会显示



操作说明书给工程师提供了实践指南

The screenshot shows the IEEE Xplore search results page. At the top, there is a navigation bar with links for Home, Login, Logout, Access Information, Alerts, Sitemap, and Help. Below this is a 'Welcome Research Account' banner with the IEEE logo. The main content area displays search results for the query '(java)<in>metadata', indicating 5086 matches out of 1461305 documents. A sidebar on the left contains 'Search Options' (View Session History, New Search) and a 'Key' section listing various IEEE publications like JIIL, CHIF, and STD. The main results area includes a 'Modify Search' section with a search box containing '(java)<in>metadata' and a 'Display Format' section with radio buttons for 'Citation' (selected) and 'Citation & Abstract'. Below this is a row of category buttons: IEEE IET, BOOKS, Expert How, Application Notes, and Scholar Univer. The 'Application Notes' button is circled in red. A red box on the right contains the text 'Links direct users to the application notes hosted outside IEEE Xplore', with red arrows pointing from the text to the 'Application Notes' button and the 'DataCompression.info' link in the search results.

Links direct users to the application notes hosted outside IEEE Xplore

技术纵览使得工程师们可以学习到自身领域之外的知识

Coming Soon!



- 查看领域内专家的意见
- 也可直接连接到 IEEE Xplore 查看一些相关的论文资料

The screenshot displays the IEEE Xplore website interface. At the top, there is a navigation bar with links for Home, Login, Logout, Access Information, Alerts, Sitemap, and Help. Below this, a blue banner reads 'Welcome Research Account' and features the IEEE logo. A secondary navigation bar includes 'Browse Technology Surveys', 'BROWSE', 'SEARCH', 'IEEE XPLORE GUIDE', and 'SUPPORT'. The main content area shows a survey titled 'CAD Algorithms, Methods and Tools For Low-Power Circuits and Systems' edited by Enrico Macii. The page includes a sidebar with the CEDA logo and contact information for Enrico Macii, Wolfgang Hebel, and Marios Papaefthymiou. The main text area contains 'Survey Sections' with five numbered sections and an 'Abstract' section discussing low power consumption in modern electronic devices.

检索结果栏与之前相比也多了
一些链接更大限度的方便了用户

Coming Soon!



A screenshot of a search results page. At the top, there is a 'Modify Search' section with a search box containing '(java<in>metadata)' and a 'Search' button. Below this is a checkbox for 'Check to search only within this results set' and a 'Display Format' section with radio buttons for 'Citation' (selected) and 'Citation & Abstract'. Below the search section are buttons for 'view selected items', 'Select All', and 'Deselect All', along with 'View: 1-25 | 26'. The main content area shows two search results. The first result is '1. Java, Java, Java' by Sabharwal, C.L., from 'Potentials, IEEE', Volume 17, Issue 3, Aug.-Sept. 1998, pages 33-37. It includes links for 'AbstractPlus | Full Text: PDF(1696 KB)', 'IEEE JUIL', and 'Rights and Permissions'. A blue arrow points from the 'view selected items' button to the first result. The second result is '2. Solving the Java object storage problem' by Barry, D.; Stanienda, T., from 'Computer', Volume 31, Issue 11, Nov. 1998, pages 33-40. It also includes links for 'AbstractPlus | Full Text: PDF(260 KB)', 'IEEE JUIL', and 'Rights and Permissions'.

附件的文献引文下载选择



The screenshot shows the IEEE Xplore interface for the article "Time-Optimal Control of a Particle in a Dielectrophoretic System". The "Download this citation" section is highlighted with a red circle. The dropdown menu is open, showing options: Citation & Abstract (selected), ASCII Text, EndNote, ProCite, RefMan, RefWorks, BibTex, and ASCII Text. A red line points from this section to a text box on the right.

Reworks
与 BibTex
被添加到
引用现在选择项中



IEEE Xplore 正在快速发展

2007年4月—8月间IEEE 暂时不会推出新的升级版本

- 原因是要与IEEE新的商业系统进行整合

- 超链接

- 用户可以直接连接到问题的解答者, 例如 SFX

- 个性化

- 关键词, 保存检索结果

- 作者网络

- 作者和联合作者的详细信息

- 检索模式的升级

- “did you mean”这样的提示用语, 同义词列表, 字典

- 针对研究所的教育课程包

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3. 避免重复开数据库检索视窗查询资料库
4. 尽量利用另存新档方式下载一篇以上文章(在**FULL TEXT ARTICLE**连接前按鼠标右鍵)
5. 阅读下载全文文章前，先看摘要确认文章是否与研究相关
6. 利用增加关键字与条件以缩小搜寻结果
7. 数据库查询完毕确实登出(左上角之**LOG OUT**)





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http://ieeexplore.ieee.org/Xplore/dynhome.jsp

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RELEASE 2.4

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Cookies Enabled

Indexed by Inspec

1.确认连线网址是否正确？

正确网址：

WWW.IEEE.ORG/IEEEXPLORE
WWW.IEEXPLORE.IEEE.ORG
IEEE.ORG/IEEEXPLORE
IEEEXPLORE.IEEE.ORG

2.确认贵单位名称是否在此处出现？
沒有出現代表此电脑的
对外连线IP或代理服务器
有无全限使用数据库

3. Cookies Enabled!

在网址输入处输入：ieeexplore.ieee.org/servlet/SnoopServlet

查看此电脑对外连线的IP或代理服务器的IP是否为单位内以设IEL连线之IP



Embedded information in the HTTP Request

Protocol	HTTP/1.1
Scheme	http
Server Name	www.ieeexplore.ieee.org
Server Port	80
Server Info	WebLogic WebLogic Server 6.1 SP5 04/21/2003 22:50:41 #253745
Remote Addr	211.78.165.131
Remote Host	adsl-211-78-165-131.js.sparqnet.net
Character Encoding	null
Content Type	null

Headers in the HTTP.REQUEST

host	www.ieeexplore.ieee.org
user-agent	Mozilla/5.0 (Windows; U; Windows NT 5.0; zh-TW; rv:1.7.5) Gecko/20041119 Firefox/1.0
accept	text/xml,application/xml,application/xhtml+xml,text/html;q=0.9,text/plain;q=0.8,image/png,*/*;q=0.5
accept-language	zh-tw,en-us;q=0.8,en;q=0.5,zh;q=0.3
accept-encoding	gzip,deflate
accept-charset	Big5,utf-8;q=0.7,*;q=0.7
keep-alive	300
cookie	xplhomepage=true; prname=notMDL; instNm=IHS_ASIA_IEL; ERIGHTS=-4625605466190752415IHSASIAIEL; username=IHSASIAIEL; JSESSIONID=Cfv7GJAdBgYSI4jNeG4I8asr2jxhO5s2W9YegNQMIbB7pj6g2jh-11480683571xpl03-1.ieee.org!801-1
Connection	Keep-Alive
WL-Proxy-SSL	false
WL-Proxy-Client-IP	211.78.165.131
Proxy-Path-Translated	/webapps/hetscape/fws60sp4/docs/servlet/SnoopServlet
Proxy-Path-Translated-Base	/webapps/hetscape/fws60sp4/docs/servlet
Proxy-Remote-User	-
Proxy-Auth-Type	basic
X-WebLogic-Request-ClusterInfo	true
X-WebLogic-KeepAliveSecs	30

Cookies in the HTTP.REQUEST

xplhomepage	true
-------------	------

完成



IEL 连线设定确认步骤



在网址输入处输入：ieeexplore.ieee.org/servlet/SnoopServlet后

1.如发现**REMOTE ADD.** 或**REMOTE HOST** 不是贵单位内先前设定的**IP**，请先与贵单位电算中心人员联络，请他们确认此陌生**IP**是否为校园内之**PROXY**更改，增加或变更的新**IP**或是其他网络中心的**IP**。如确定是新增或更改**IP**请与我们联系，我们会增加新的**IP** 设定。

2.如发现**REMOTE ADD.** 或**REMOTE HOST** 是贵单位内先前设定之**IP**，请将此画面与在资料库被要求输入帐号密码之画面贴在**WORD.**上寄给我们(pauline.chan@ihs.com)，我们将请国外尽速为您解决问题。



QUESTIONS?

IHS – 北京代表处

联络人：陈 智

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电子邮件：richard@ihs.cn

IHS 亞太區

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